

# MBL800E33D

Silicon N-channel IGBT

## FEATURES

- \* High thermal fatigue durability.( $\Delta T_c=70^\circ\text{C}$ , $N>30,000$ cycles)
- \* High speed, low loss IGBT module.
- \* Low noise due to built-in free-wheeling diode
  - ultra soft fast recovery diode(USFD).
- \* Low driving power due to low input capacitance MOS gate.
- \* High reliability, high durability module.
- \* Isolated heat sink(terminal to base).

## ABSOLUTE MAXIMUM RATINGS ( $T_c=25^\circ\text{C}$ )

| Item                      | Symbol            | Unit             | MBL800E33D         |
|---------------------------|-------------------|------------------|--------------------|
| Collector Emitter Voltage | V <sub>CES</sub>  | V                | 3,300              |
| Gate Emitter Voltage      | V <sub>GES</sub>  | V                | $\pm 20$           |
| Collector Current         | DC                | I <sub>C</sub>   | 800                |
|                           | 1ms               | I <sub>Cp</sub>  | 1,600              |
| Forward Current           | DC                | I <sub>F</sub>   | 800                |
|                           | 1ms               | I <sub>FM</sub>  | 1,600              |
| Junction Temperature      | T <sub>j</sub>    | $^\circ\text{C}$ | -40 ~ +125         |
| Storage Temperature       | T <sub>stg</sub>  | $^\circ\text{C}$ | -40 ~ +125         |
| Isolation Voltage         | V <sub>ISO</sub>  | V <sub>RMS</sub> | 6,000(AC 1 minute) |
| Screw Torque              | Terminals (M4/M8) | -                | 2/10 (1)           |
|                           | Mounting (M6)     | -                | 6 (2)              |

Notes: (1) Recommended Value  $1.8\pm 0.2/9\pm 1\text{N}\cdot\text{m}$ (2) Recommended Value  $5.5\pm 0.5\text{N}\cdot\text{m}$ 

## ELECTRICAL CHARACTERISTICS

### 1) IGBT + FWD

| Item                                 | Symbol               | Unit                 | Min. | Typ. | Max.  | Test Conditions  |
|--------------------------------------|----------------------|----------------------|------|------|-------|--|
| Collector Emitter Cut-Off Current    | I <sub>CES</sub>     | mA                   | -    | -    | 12.0  | V <sub>CE</sub> =3,300V, V <sub>GE</sub> =0V, T <sub>j</sub> =25 $^\circ\text{C}$                  |
| Gate Emitter Leakage Current         | I <sub>GES</sub>     | nA                   | -500 | -    | +500  | V <sub>GE</sub> = $\pm 20\text{V}$ , V <sub>CE</sub> =0V, T <sub>j</sub> =25 $^\circ\text{C}$      |
| Collector Emitter Saturation Voltage | V <sub>CE(sat)</sub> | V                    | -    | 4.2  | 5.2   | I <sub>C</sub> =800A, V <sub>GE</sub> =15V, T <sub>j</sub> =125 $^\circ\text{C}$                   |
| Gate Emitter Threshold Voltage       | V <sub>GE(TO)</sub>  | V                    | 4.5  | 6.0  | 7.0   | V <sub>CE</sub> =10V, I <sub>C</sub> =800mA, T <sub>j</sub> =25 $^\circ\text{C}$                   |
| Input Capacitance                    | C <sub>ies</sub>     | nF                   | -    | 75   | -     | V <sub>CE</sub> =10V, V <sub>GE</sub> =0V, f=100kHz, T <sub>j</sub> =25 $^\circ\text{C}$           |
| Internal Gate Resistance             | R <sub>ge</sub>      | $\Omega$             | -    | 1.8  | -     |  |
| Switching Times                      | Rise Time            | t <sub>r</sub>       | -    | 1.9  | 3.1   | V <sub>CC</sub> =1,650V, I <sub>C</sub> =800A  |
|                                      | Turn On Time         | t <sub>on</sub>      | -    | 2.4  | 3.3   | L=120nH  |
|                                      | Fall Time            | t <sub>f</sub>       | -    | 1.0  | 2.5   | R <sub>G</sub> =4.7 $\Omega$ (3)   |
|                                      | Turn Off Time        | t <sub>off</sub>     | -    | 3.0  | 5.1   | V <sub>GE</sub> = $\pm 15\text{V}$ , T <sub>j</sub> =125 $^\circ\text{C}$                          |
| Peak Forward Voltage Drop            | V <sub>FM</sub>      | V                    | -    | 2.5  | 3.0   | -I <sub>C</sub> =800A, V <sub>GE</sub> =0V, T <sub>j</sub> =125 $^\circ\text{C}$                   |
| Reverse Recovery Time                | t <sub>rr</sub>      | $\mu\text{s}$        | -    | 0.6  | 1.1   | V <sub>CC</sub> =1,650V, I <sub>F</sub> =800A (4)<br>L=120nH, T <sub>j</sub> =125 $^\circ\text{C}$ |
| Thermal Impedance                    | IGBT                 | R <sub>th(j-c)</sub> | -    | -    | 0.013 | Junction to case   |
|                                      | FWD                  | R <sub>th(j-c)</sub> | -    | -    | 0.026 |  |

### 2) DIODE

| Item                              | Symbol               | Unit          | Min. | Typ. | Max.  | Test Conditions  |
|-----------------------------------|----------------------|---------------|------|------|-------|--|
| Collector Emitter Cut-Off Current | I <sub>AKS</sub>     | mA            | -    | -    | 12.0  | V <sub>AK</sub> =3,300V, T <sub>j</sub> =25 $^\circ\text{C}$   |
| Peak Forward Voltage Drop         | V <sub>F</sub>       | V             | -    | 2.9  | 3.4   | I <sub>F</sub> =800A, T <sub>j</sub> =125 $^\circ\text{C}$ At Main terminal<br>(Terminal resistance:0.5m $\Omega$ typical) |
| Reverse Recovery Time             | t <sub>rr</sub>      | $\mu\text{s}$ | -    | 0.6  | 1.1   | I <sub>F</sub> =800A, V <sub>CC</sub> =1,650V (4)<br>L=120nH, T <sub>j</sub> =125 $^\circ\text{C}$                         |
| Thermal Impedance                 | R <sub>th(j-c)</sub> | K/W           |      |      | 0.026 | Junction to case   |

Notes: (3) R<sub>G</sub> value is the test condition's value for decision of the switching times, not recommended value. Please, determine the suitable R<sub>G</sub> value after the measurement of switching waveforms(overshoot voltage, etc.)with appliance mounted.  
(4)Counter arm IGBT V<sub>GE</sub>= $\pm 15\text{V}$

\* Please contact our representatives at order.

\* For improvement, specifications are subject to change without notice.

\* For actual application, please confirm this spec sheet is the newest revision.

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## DEFINITION OF TEST CIRCUIT

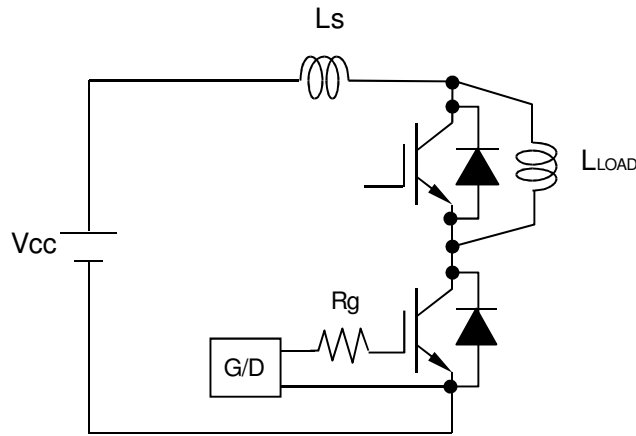


Fig.1 Switching test circuit

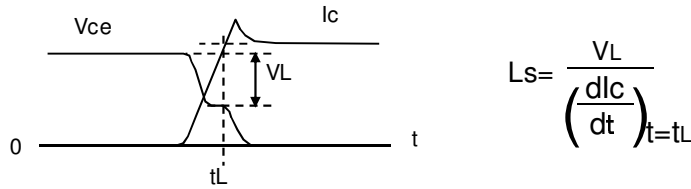


Fig.2 Definition of Ls

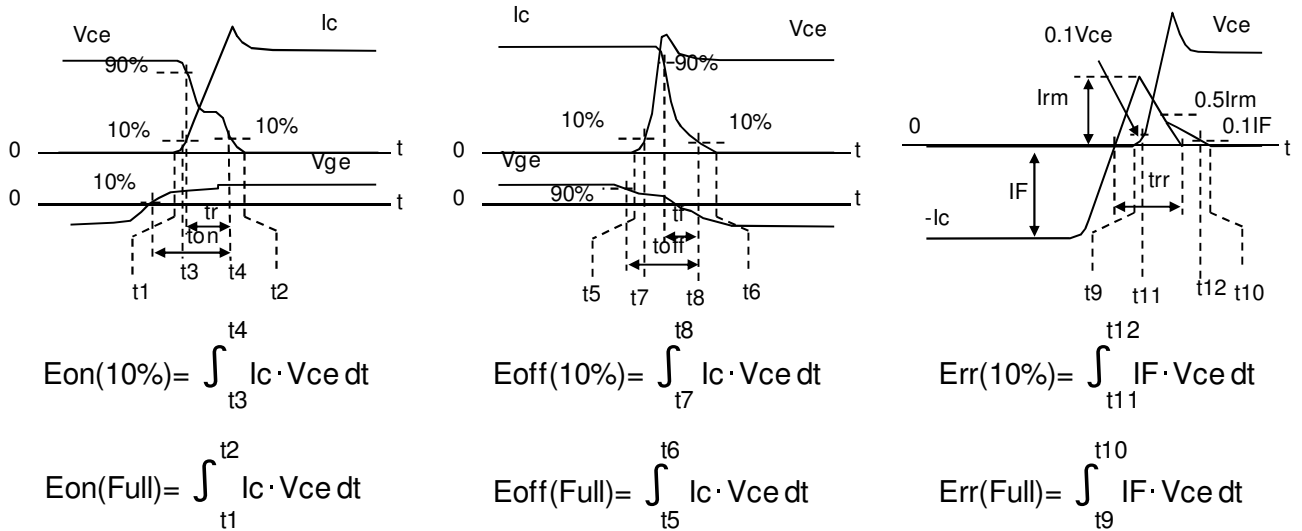
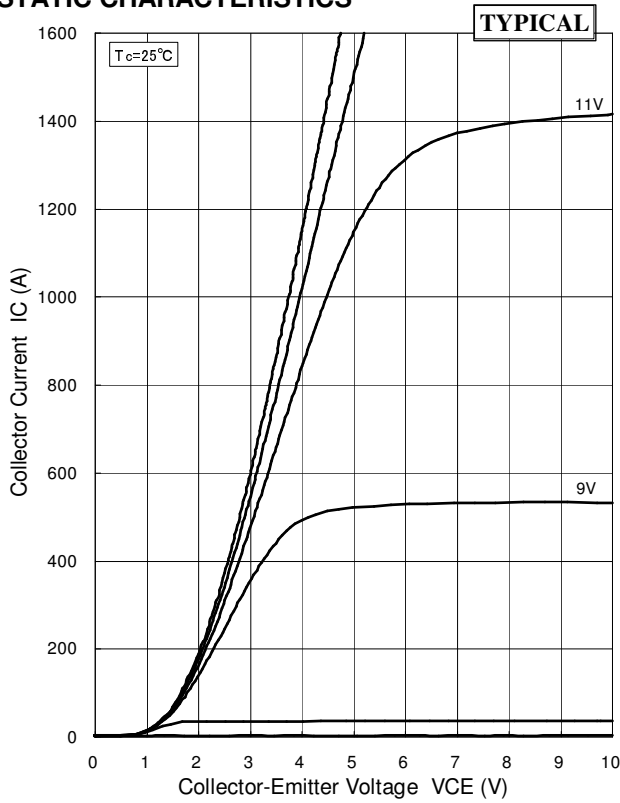


Fig.3 Definition of switching loss

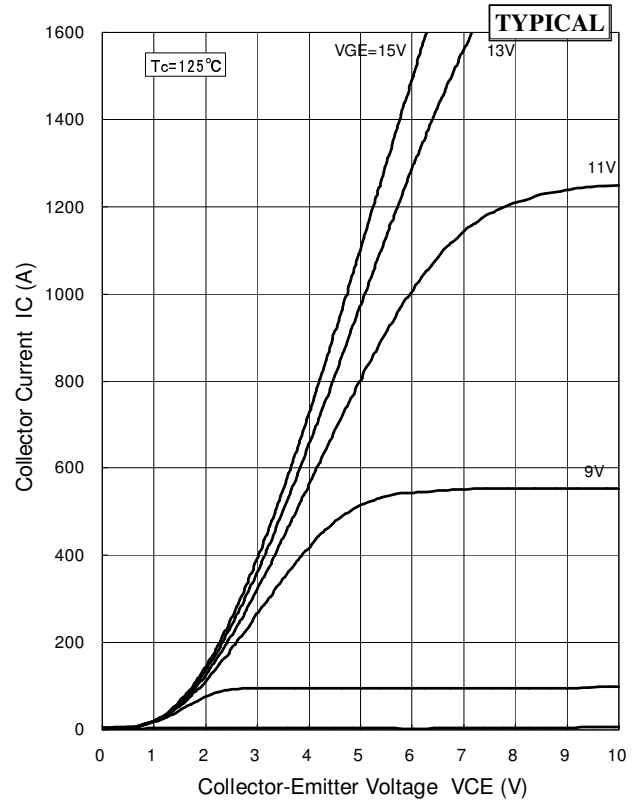
# MBL800E33D

## CHARACTERISTICS CURVE

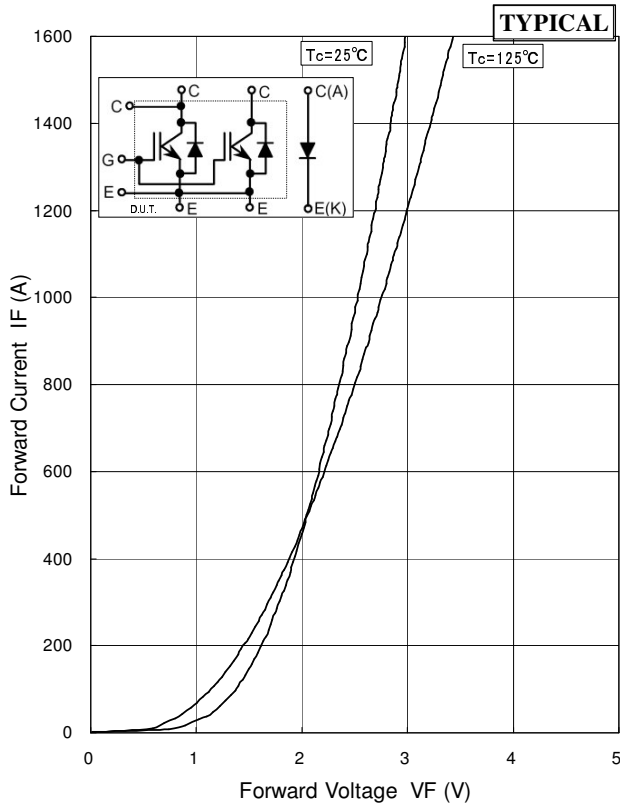
### STATIC CHARACTERISTICS



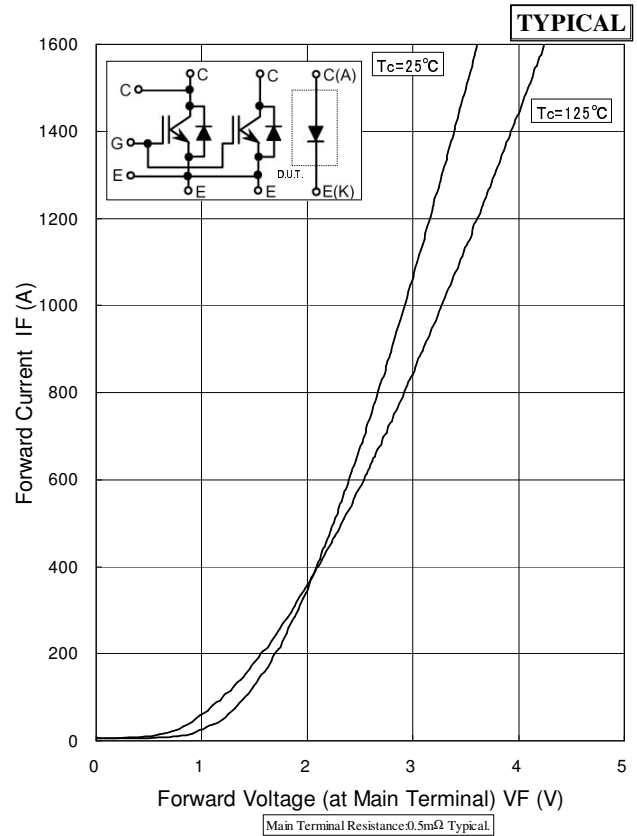
Collector Current vs. Collector to Emitter Voltage



Collector Current vs. Collector to Emitter Voltage



Forward Voltage of free-wheeling diode

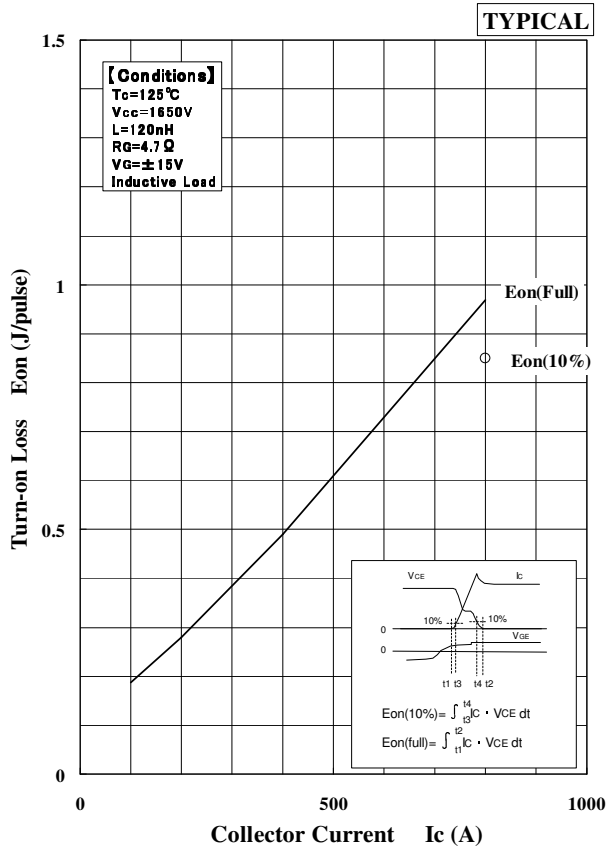


Forward Voltage of chopper diode

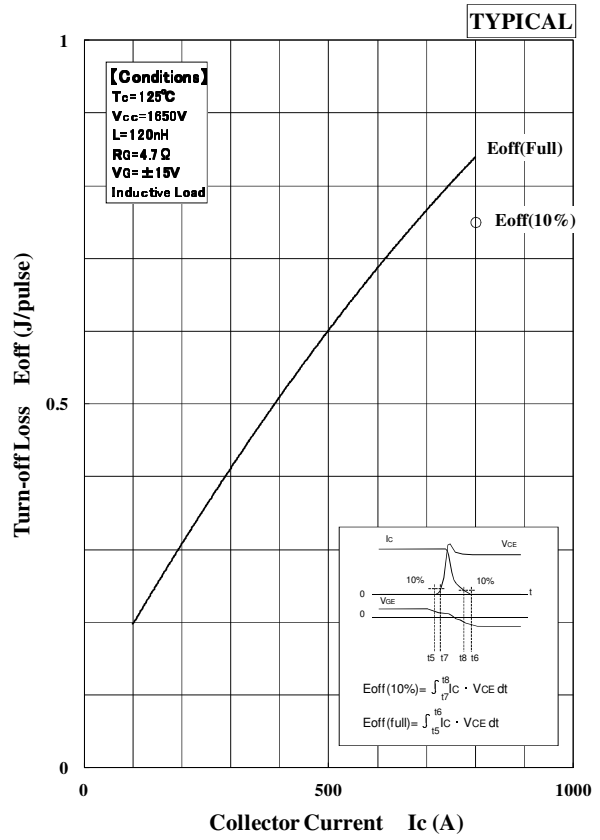
# MBL800E33D

## DYNAMIC CHARACTERISTICS

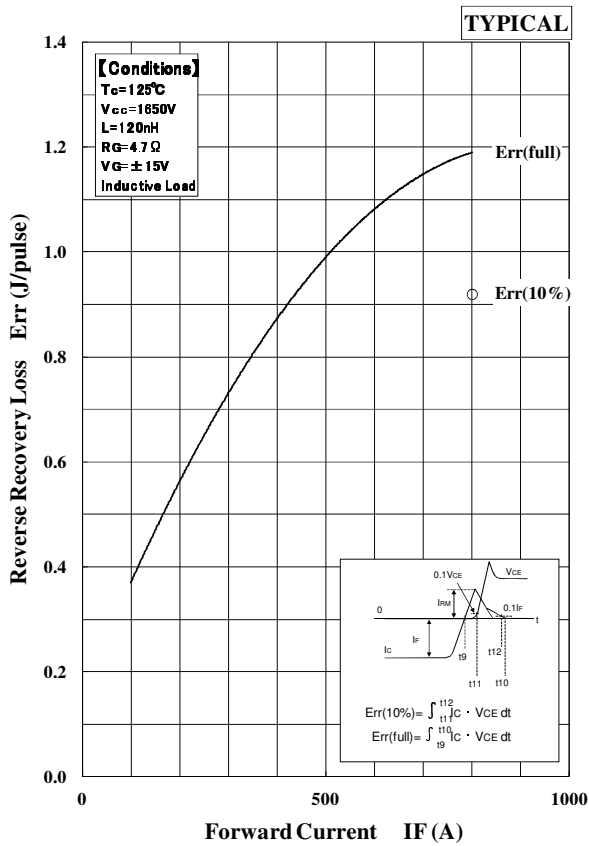
### DEPENDENCE OF CURRENT



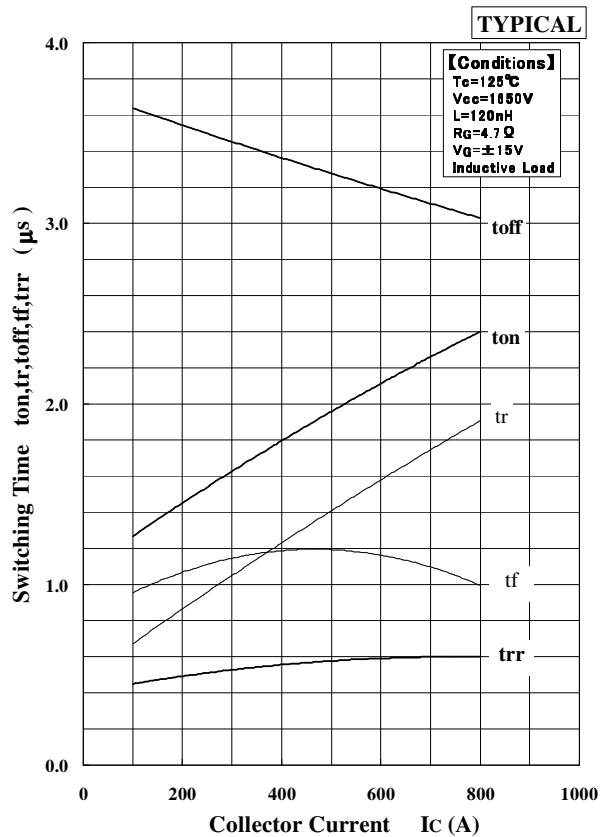
Turn-on Loss vs. Collector Current



Turn-off Loss vs. Collector Current



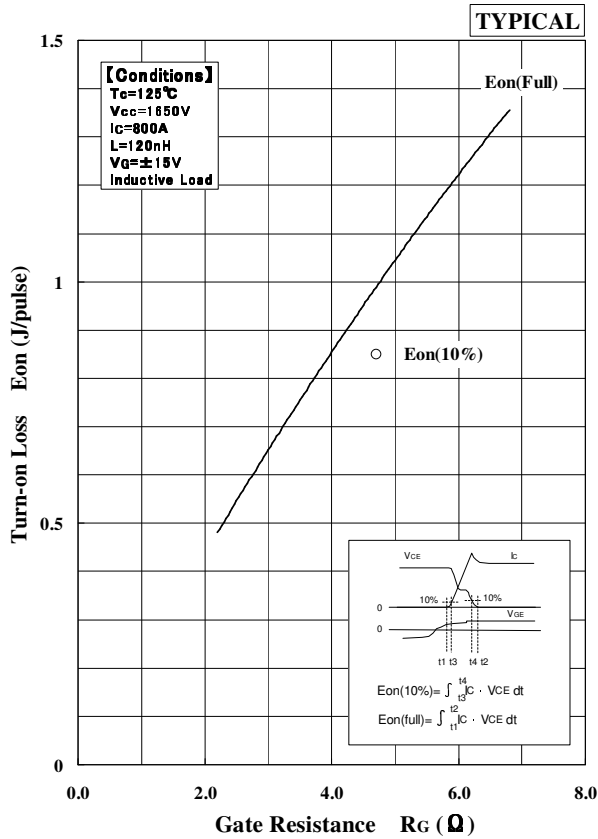
Recovery Loss vs. Forward Current



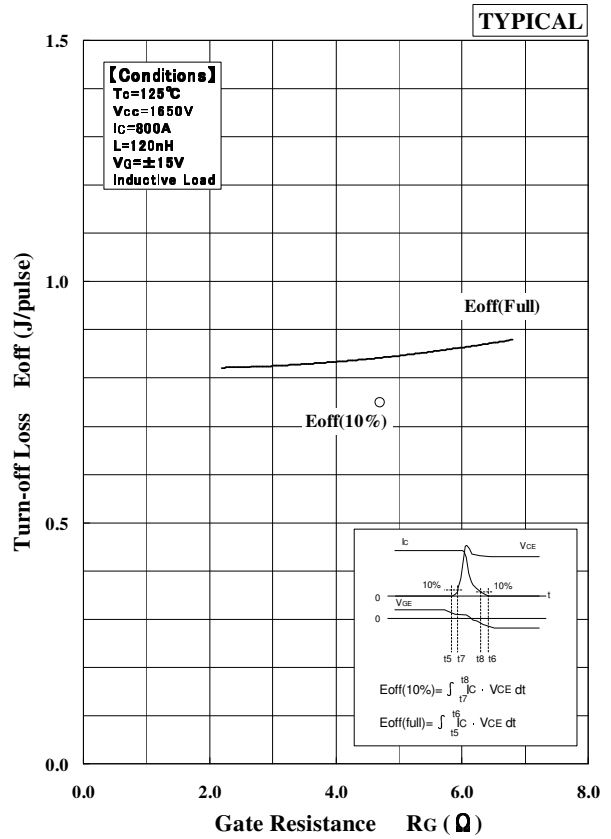
Switching Time vs. Collector Current

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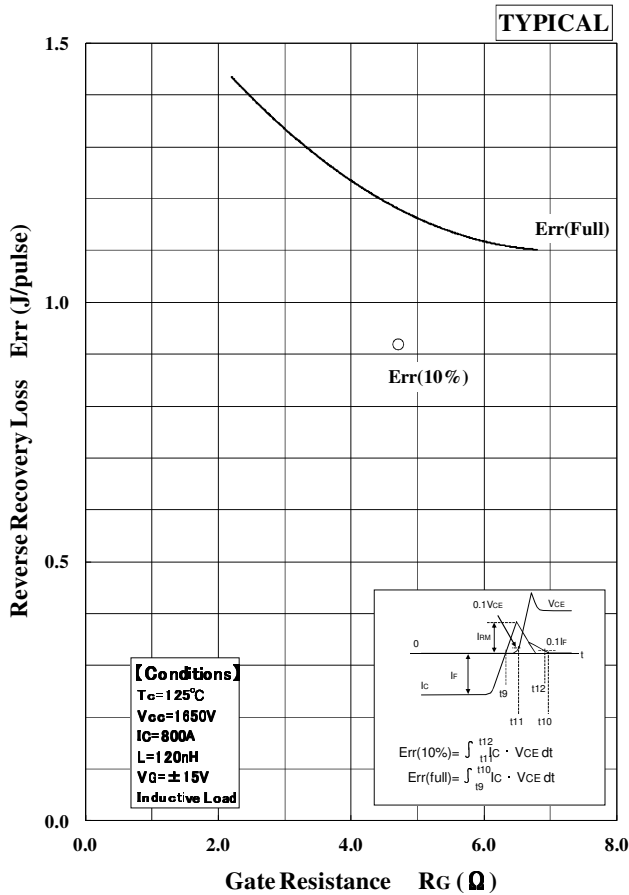
## DEPENDENCE OF RG



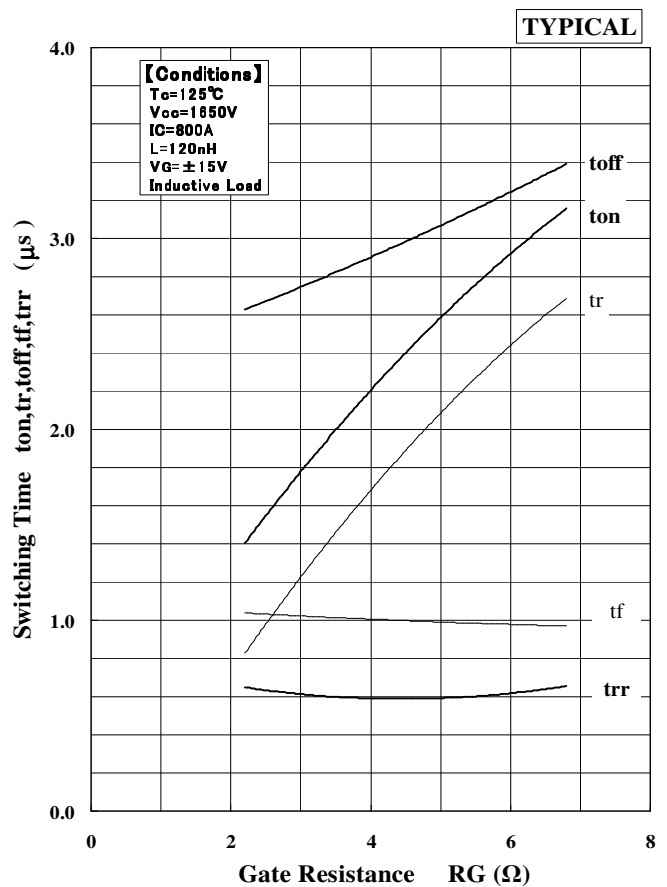
Turn-on Loss vs. Gate Resistance



Turn-off Loss vs. Gate Resistance



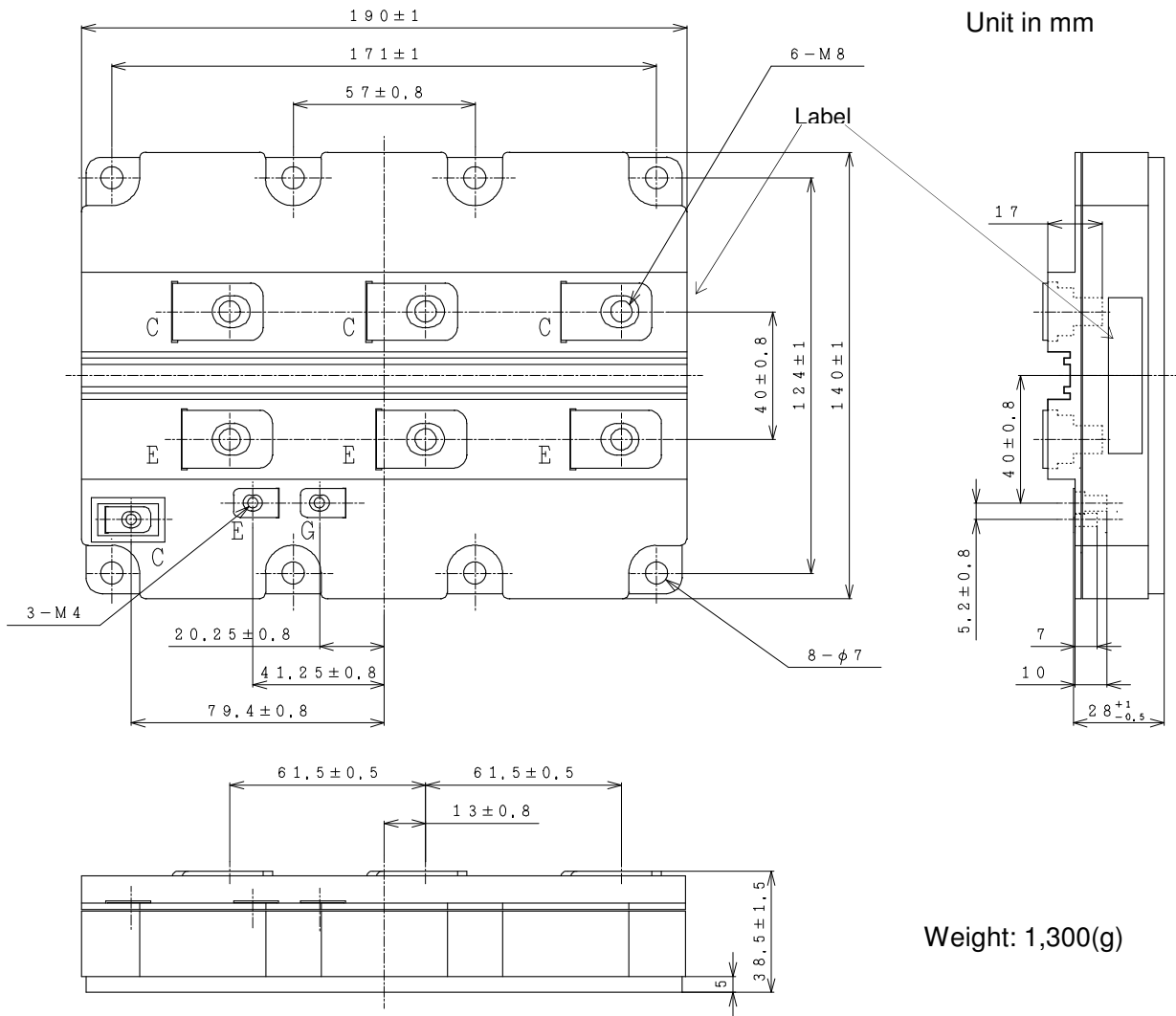
Recovery Loss vs. Gate Resistance



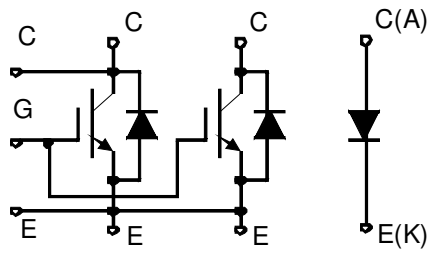
Switching Time vs. Gate Resistance

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## PACKAGE OUTLINE DRAWING



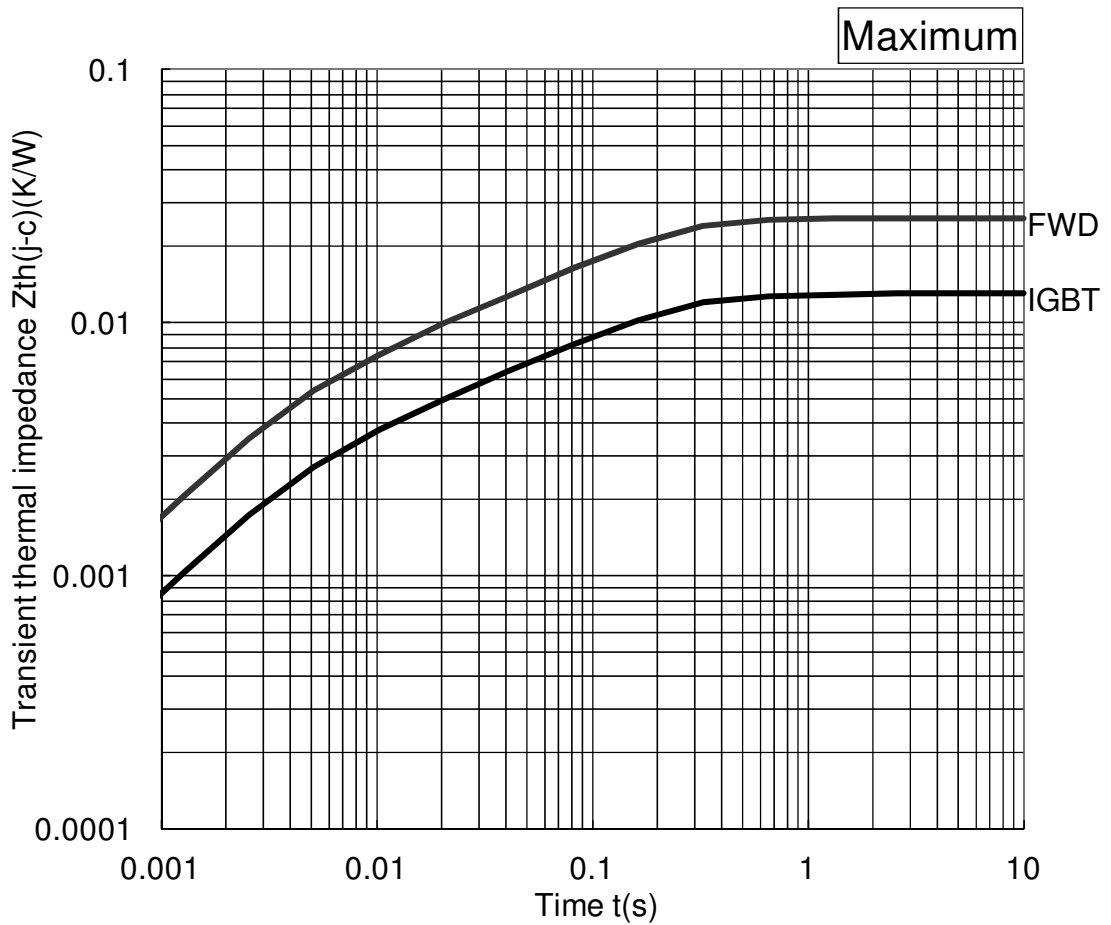
Weight: 1,300(g)



Circuit diagram

# MBL800E33D

## TRANSIENT THERMAL IMPEDANCE



Transient Thermal Impedance Curve

### Material declaration

Please note the following materials are contained in the product, in order to keep characteristic and reliability level.

| Material                    | Contained part |
|-----------------------------|----------------|
| Lead (Pb) and its compounds | Solder         |

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## HITACHI POWER SEMICONDUCTORS

### Notices

1. The information given herein, including the specifications and dimensions, is subject to change without prior notice to improve product characteristics. Before ordering, purchasers are advised to contact Hitachi sales department for the latest version of this data sheets.
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